

# PATENT ABSTRACTS OF JAPAN

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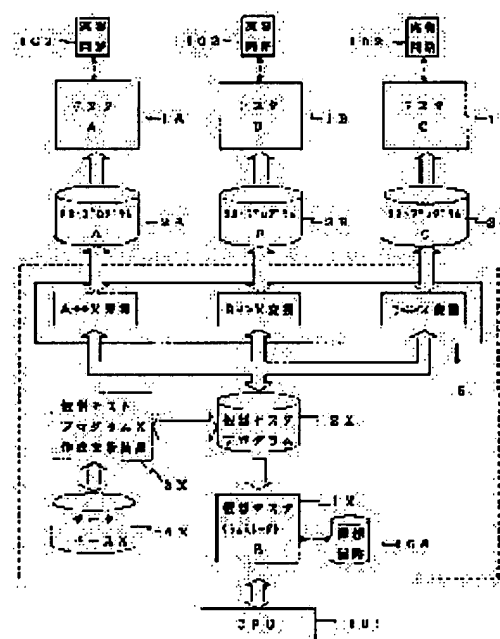
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## (54) TEST SYSTEM

### (57)Abstract:

**PURPOSE:** To improve the efficiency of debugging work and to shorten the development period of a circuit device by converting test program description for a virtual tester for simulating an operation test of a virtual circuit into test program description for a real tester.

**CONSTITUTION:** Real testers 1A to 1C respectively execute the operation tests of a real circuit 102 based upon respective test programs 2A to 2C describing test contents. A virtual tester 1X simulates an operation test of a virtual circuit 103 expressed like software by a network list or the like based upon a test program 2X and a program preparation supporting device 3X supports the preparation and correction of the test program 2X. A program conversion device 5 converts the description of the test program 2X for the tester 1X into the description of the test programs 2A to 2C for the testers 1A to 1C. Consequently the debugging of the test programs 2A to 2C can separately be executed from that of the circuit device and trial-and-error elements can be reduced.



## LEGAL STATUS

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